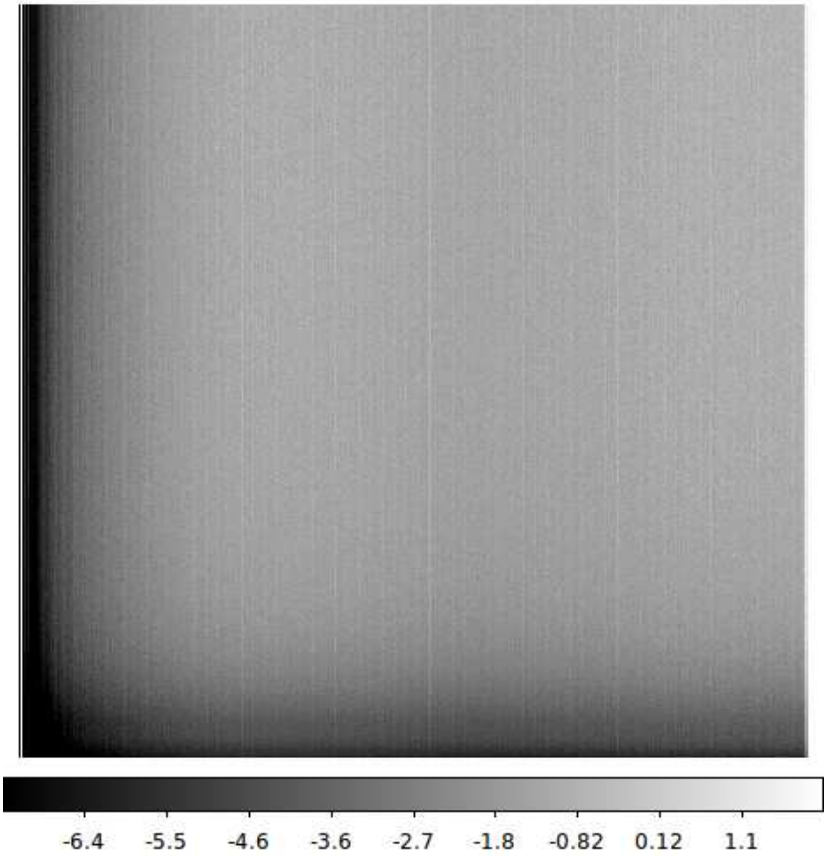
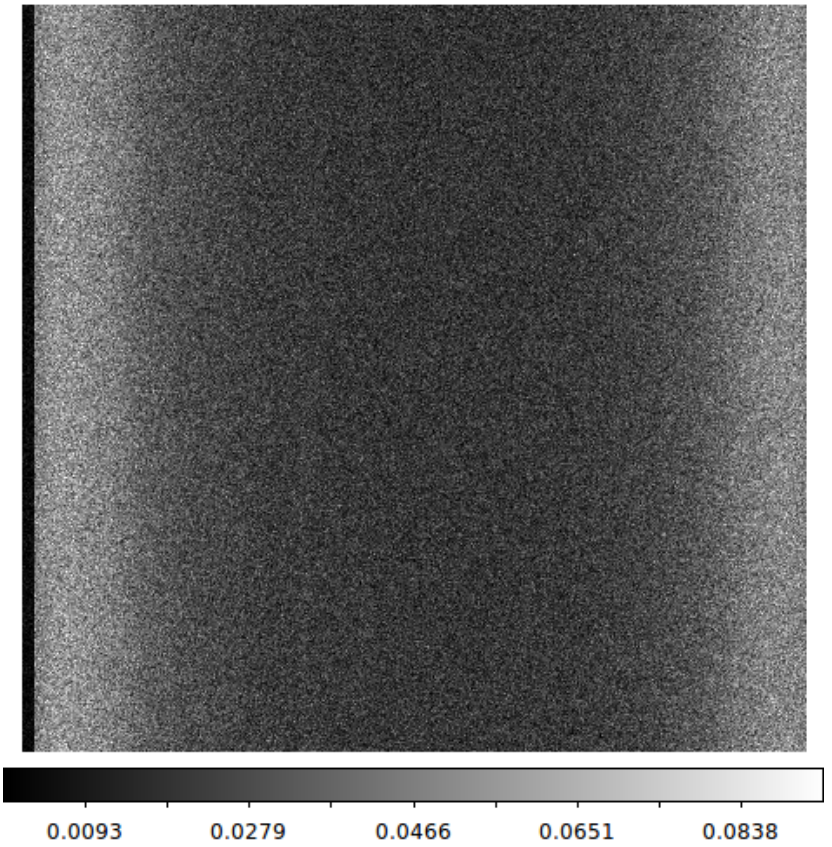
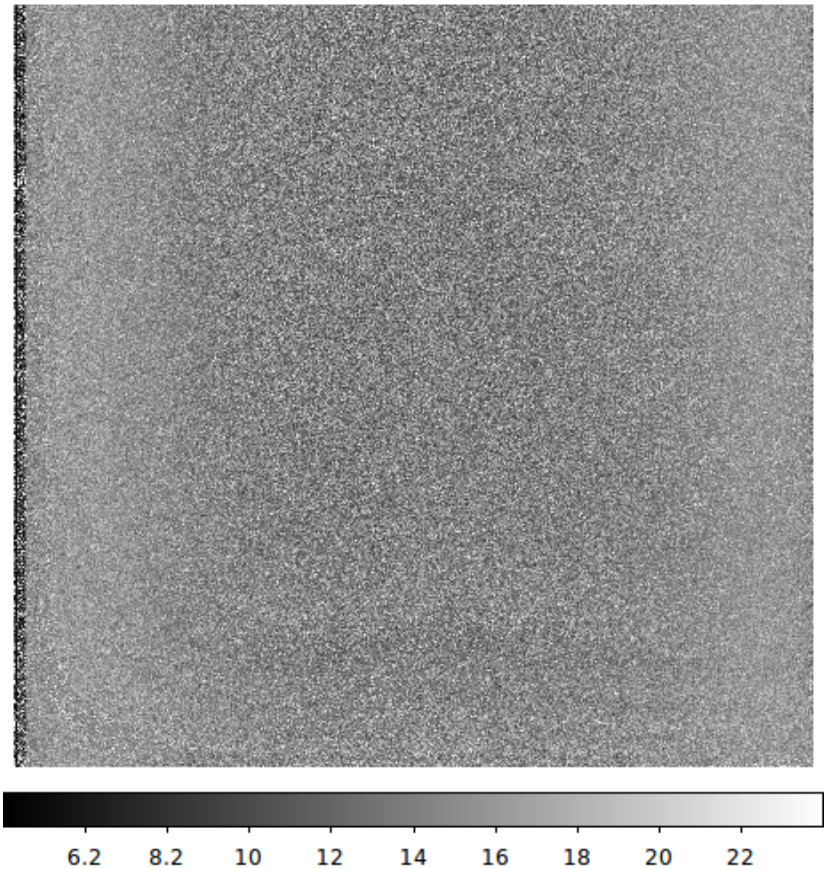


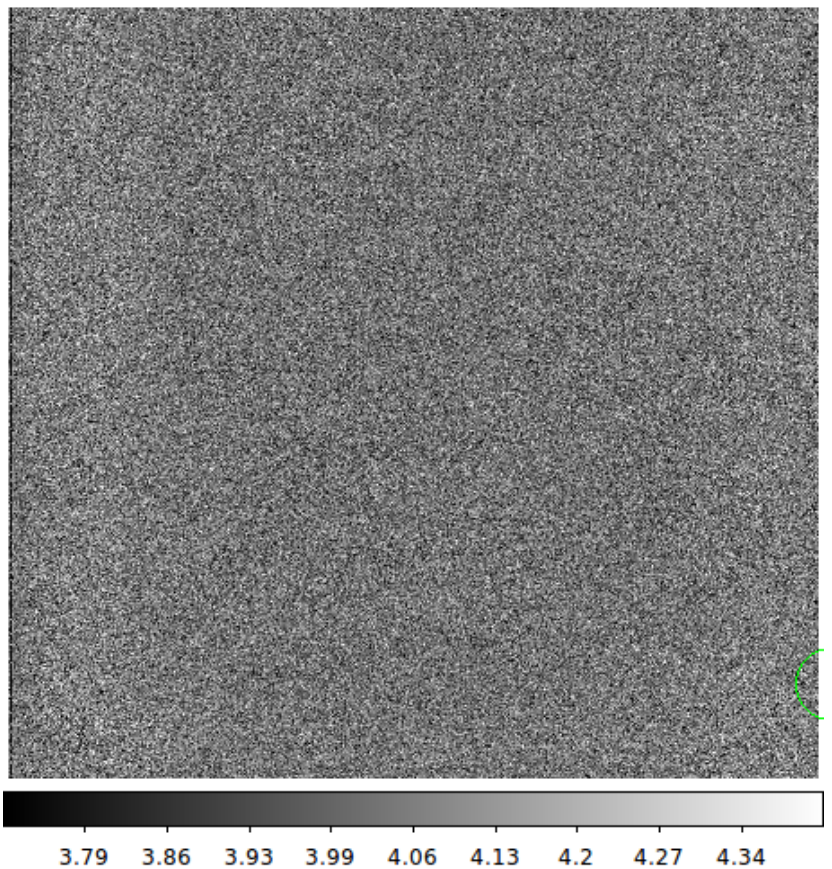
(a) Bias pattern



(b) Spurious charge



(c) EM gain



(d) Readout noise